## 山东迪一电子科技有限公司



# HER101G – HER108G 🚱 📈

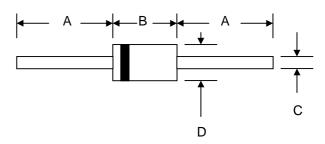
### 1.0A GLASS PASSIVATED ULTRAFAST DIODE

### Features

- Glass Passivated Die Construction
- Low Forward Voltage Drop
- High Current Capability
- High Reliability
- High Surge Current Capability

### **Mechanical Data**

- Case: Molded Plastic
- Terminals: Plated Leads Solderable per MIL-STD-202, Method 208
- Polarity: Cathode Band
- Weight: 0.34 grams (approx.)
- Mounting Position: Any
- Marking: Type Number
- Lead Free: For RoHS / Lead Free Version,



DO-41							
Dim	Min	Max					
Α	25.4	_					
В	4.06	5.21					
С	0.71	0.864					
D	2.00	2.72					
All Dimensions in mm							

### Maximum Ratings and Electrical Characteristics @T<sub>A</sub>=25°C unless otherwise specified

Single Phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

Characteristic	Symbol	HER 101G	HER 102G	HER 103G	HER 104G	HER 105G	HER 106G	HER 107G	HER 108G	Unit
Peak Repetitive Reverse Voltage Working Peak Reverse Voltage DC Blocking Voltage	Vrrm Vrwm Vr	50	100	200	300	400	600	800	1000	V
RMS Reverse Voltage	VR(RMS)	35	70	140	210	280	420	560	700	V
Average Rectified Output Current (Note 1) $@T_A = 55^{\circ}C$	lo	1.0							A	
Non-Repetitive Peak Forward Surge Current 8.3ms Single half sine-wave superimposed on rated load (JEDEC Method)	IFSM	60							A	
Forward Voltage $@I_F = 2.0A$	Vfm	1.0 1.3 1.7						V		
Peak Reverse Current $@T_A = 25^{\circ}C$ At Rated DC Blocking Voltage $@T_A = 100^{\circ}C$	Iгм	5.0 100							μA	
Reverse Recovery Time (Note 2)	trr	50 75						nS		
Typical Junction Capacitance (Note 3)	Cj	60 40						pF		
Operating Temperature Range	Tj	-65 to +150							°C	
Storage Temperature Range	Тѕтс	-65 to +150						°C		

#### \*Glass passivated forms are available upon request

Note: 1. Leads maintained at ambient temperature at a distance of 9.5mm from the case

2. Measured with IF = 0.5A, IR = 1.0A, IRR = 0.25A. See figure 5.

3. Measured at 1.0 MHz and applied reverse voltage of 4.0V D.C.

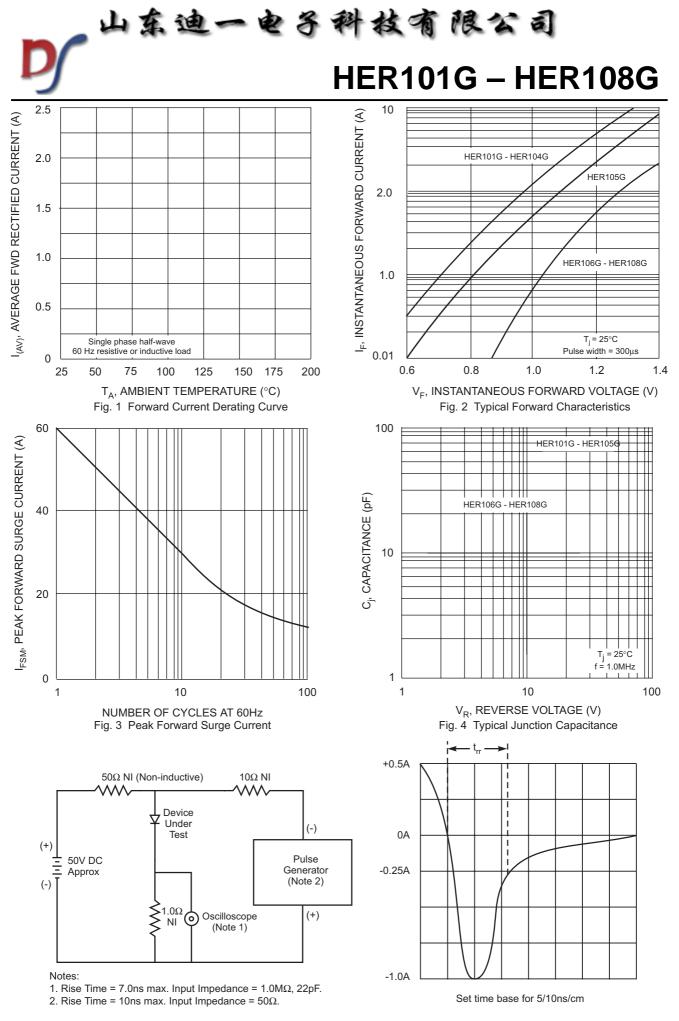


Fig. 5 Reverse Recovery Time Characteristic and Test Circuit